International Rectifier

Rectifier IRLZ34NPbF

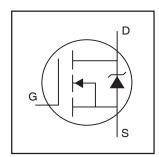
HEXFET® Power MOSFET

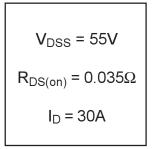
- Logic-Level Gate Drive
- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

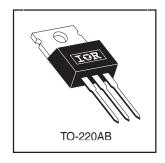
Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve the lowest possible on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.







Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	30	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	21	A
I _{DM}	Pulsed Drain Current [0]	110	
P _D @T _C = 25°C	Power Dissipation	68	W
	Linear Derating Factor	0.45	W/°C
V _{GS}	Gate-to-Source Voltage	±16	V
E _{AS}	Single Pulse Avalanche Energy ②	110	mJ
I _{AR}	Avalanche Current①	16	A
E _{AR}	Repetitive Avalanche Energy①	6.8	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns
TJ	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 screw.	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Min.	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case			2.2	
R _{θCS}	Case-to-Sink, Flat, Greased Surface		0.50		°C/W
R _{0JA}	Junction-to-Ambient			62]

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Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.065		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		_	0.035		V _{GS} = 10V, I _D = 16A ④
				0.046	Ω	V _{GS} = 5.0V, I _D = 16A ④
				0.060		V _{GS} = 4.0V, I _D = 14A ④
V _{GS(th)}	Gate Threshold Voltage	1.0		2.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
9 fs	Forward Transconductance	11			S	V _{DS} = 25V, I _D = 16A
_	Drain-to-Source Leakage Current			25	μA	V _{DS} = 55V, V _{GS} = 0V
IDSS				250	μΛ	V _{DS} = 44V, V _{GS} = 0V, T _J = 150°C
_	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 16V
I _{GSS}	Gate-to-Source Reverse Leakage			-100	l na l	V _{GS} = -16V
Qg	Total Gate Charge			25		I _D = 16A
Q _{gs}	Gate-to-Source Charge			5.2	nC	V _{DS} = 44V
Q _{gd}	Gate-to-Drain ("Miller") Charge			14		V_{GS} = 5.0V, See Fig. 6 and 13 \oplus
t _{d(on)}	Turn-On Delay Time		8.9			V _{DD} = 28V
t _r	Rise Time		100		ns	I _D = 16A
t _{d(off)}	Turn-Off Delay Time		21		113	$R_G = 6.5\Omega, V_{GS} = 5.0V$
t _f	Fall Time		29			R_D = 1.8 Ω , See Fig. 10 \oplus
L _D	Internal Drain Inductance	_	4.5			Between lead,
				4.5		nH
L _S	Internal Source Inductance		7.5		''''	from package
						and center of die contact
C _{iss}	Input Capacitance		880			V _{GS} = 0V
Coss	Output Capacitance		220		pF	V _{DS} = 25V
C _{rss}	Reverse Transfer Capacitance		94			f = 1.0MHz, See Fig. 5

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions						
Is	Continuous Source Current			30		MOSFET symbol						
	(Body Diode)	i —		30	Α	showing the						
I _{SM}	Pulsed Source Current			110	110	, ,	integral reverse					
	(Body Diode) ①			i —		_	_ 110	_	110	110		p-n junction diode.
V _{SD}	Diode Forward Voltage			1.3	V	T _J = 25°C, I _S = 16A, V _{GS} = 0V ⊕						
t _{rr}	Reverse Recovery Time		76	110	ns	T _J = 25°C, I _F = 16A						
Q _{rr}	Reverse RecoveryCharge		190	290	nC	di/dt = 100A/µs ⊕						
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)										

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② V_{DD} = 25V, starting T_J = 25°C, L = 610μH R_G = 25Ω, I_{AS} = 16A. (See Figure 12)
- $\label{eq:local_local_local_local} \begin{array}{l} \textcircled{3} \ I_{SD} \leq 16\text{A}, \ \text{di/dt} \leq 270\text{A}/\mu\text{s}, \ V_{DD} \leq V_{(BR)DSS}, \\ T_{J} \leq 175^{\circ}\text{C} \\ \textcircled{4} \ \text{Pulse width} \leq 300\mu\text{s}; \ \text{duty cycle} \leq 2\%. \end{array}$

International TOR Rectifier

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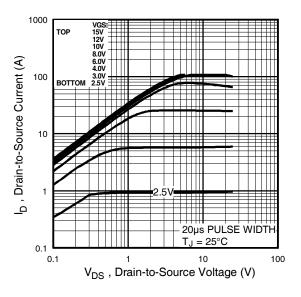


Fig 1. Typical Output Characteristics

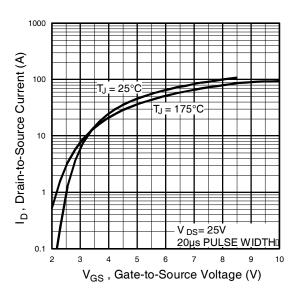


Fig 3. Typical Transfer Characteristics

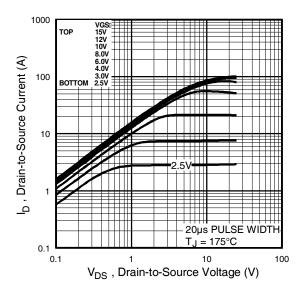


Fig 2. Typical Output Characteristics

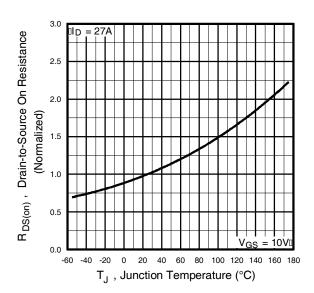


Fig 4. Normalized On-Resistance Vs. Temperature

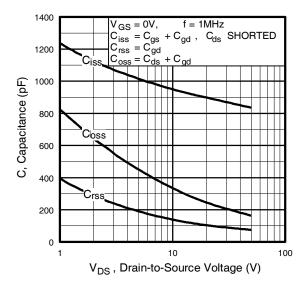


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

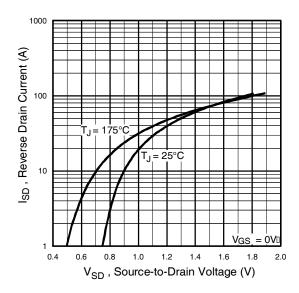


Fig 7. Typical Source-Drain Diode Forward Voltage

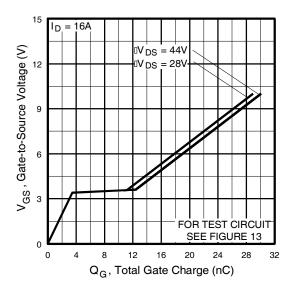


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

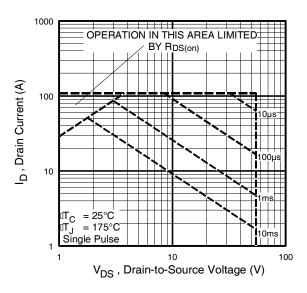


Fig 8. Maximum Safe Operating Area

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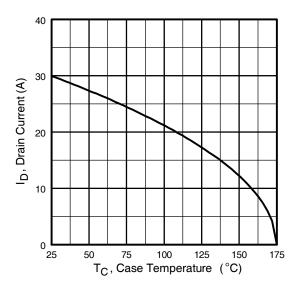


Fig 9. Maximum Drain Current Vs.
Case Temperature

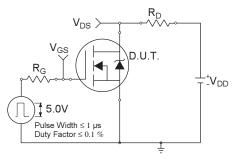


Fig 10a. Switching Time Test Circuit

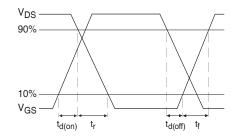


Fig 10b. Switching Time Waveforms

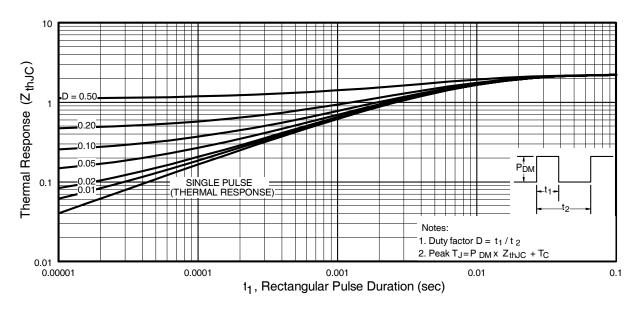


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

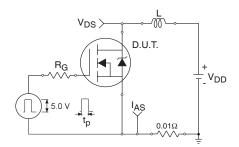


Fig 12a. Unclamped Inductive Test Circuit

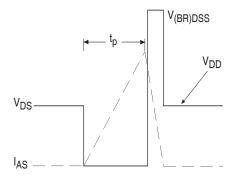


Fig 12b. Unclamped Inductive Waveforms

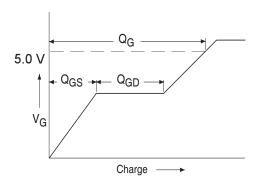


Fig 13a. Basic Gate Charge Waveform

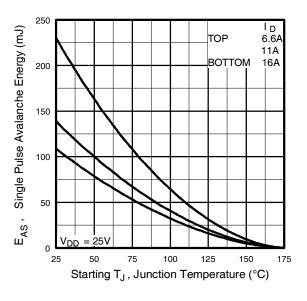


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

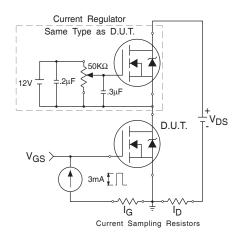
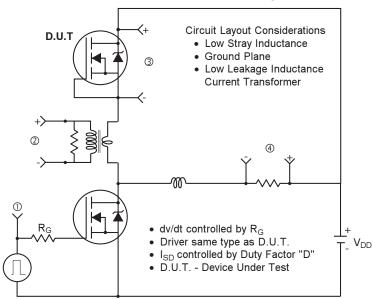


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



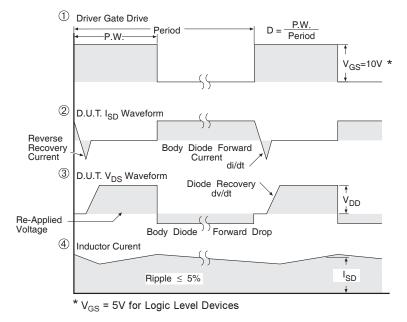
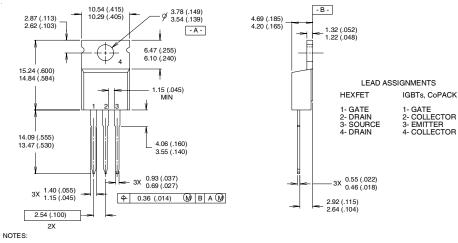


Fig 14. For N-Channel HEXFETS

TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



- 1 DIMENSIONING & TOLERANCING PER ANSI Y14.5M, 1982. 2 CONTROLLING DIMENSION: INCH
- 3 OUTLINE CONFORMS TO JEDEC OUTLINE TO-220AB.
- 4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

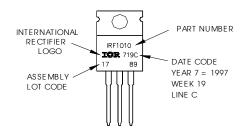
TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010

LOT CODE 1789

ASSEMBLED ON WW 19, 1997 IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position indicates "Lead-Free"



Data and specifications subject to change without notice.



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Note: For the most current drawings please refer to the IR website at: http://www.irf.com/package/

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